A diagnosable structured logic array and associated process is provided. A base cell structure is provided comprising a logic unit comprising a plurality of input nodes, a plurality of selection nodes, and an output node, a plurality of switches coupled to the selection nodes, where the switches comprise a plurality of input lines, a selection line and an output line, a memory cell coupled to the output node, and a test address bus and a program control bus coupled to the plurality of input lines and the selection line of the plurality of switches. A state on each of the plurality of input nodes is verifiably loaded and read from the memory cell. A trusted memory block is provided. The associated process is provided for testing and verifying a plurality of truth table inputs of the logic unit.
Fig. 2
Fig. 3
Begin

Load Memory Unit

Set Test Address

Set Test_Enable

Read Scan Chain

End

Fig. 5
Fig. 6
(Prior Art)
SUMMARY OF THE INVENTION

In accordance with a first aspect of the present invention, a base cell structure is provided. The base cell includes a logic unit with a plurality of input nodes, a plurality of selection nodes, and an output node. A plurality of switches are coupled to the selection nodes, where the switches include a plurality of input lines, a selection line and an output line. A memory cell is coupled to the output node. A test address bus and a program control bus are coupled to the plurality of input lines and a plurality of memory test address signals and a scan select signal are coupled to the selection line of the plurality of switches. The trusted memory block can include a buffer circuit following the scan D flip flop. In addition, the plurality of switches can comprise a triad of 2 to 1 multiplexers that are arranged in tandem.

In accordance with another aspect of the present invention, a logic structure is provided. The logic structure comprises an array of trusted logic blocks and an array of trusted memory blocks. The array of trusted logic blocks includes a logic unit comprising a plurality of input nodes, a plurality of selection nodes, and an output node. A plurality of switches are coupled to the selection nodes, where the switches comprise a plurality of input lines, a selection line and an output line. A test address bus and a program control bus are coupled to the plurality of input lines and the selection line of the plurality of switches. The array of trusted memory blocks include a plurality of input lines, a selection line and an output line. A scan D flip flop is coupled to the output line of one of the plurality of switches. A plurality of selection node input signals and a scan data signal are coupled to the plurality of input lines and a plurality of memory test address signals and a scan select signal are coupled to the selection line of the plurality of switches. The logic structure includes logic blocks of the array of trusted logic blocks arranged in tandem with each memory block of the array of trusted memory blocks. Also, the logic unit of the array of trusted logic blocks can comprise an 8x1 multiplexer. A buffer circuit can follow each of the logic units and scan D flip flops. In an exemplary embodiment, the logic structure includes non-logic structures occupying a space of the logic structure that is devoid of active logic circuits. The non-logic structures can comprise filter capacitors. Additionally, the logic structure can include 9x buffers and 3x buffers on a periphery of the logic structure.

In accordance with yet another aspect of the present invention, a logic unit comprising a plurality of input nodes, a plurality of selection nodes, an output node, and a plurality of switches coupled to the selection nodes. The switches include a plurality of input lines, a selection line and an output line. A test address bus and a program control bus are coupled to the plurality of input lines and the selection line of the plurality of switches. The array of trusted memory blocks includes a plurality of input lines, a selection line and an output line. A scan D flip flop is coupled to the output line of one of the plurality of switches. A plurality of selection node input signals and a scan data signal are coupled to the plurality of input lines and a plurality of memory test address signals and a scan select signal are coupled to the selection line of the plurality of switches. In one embodiment, each logic block of the array of trusted logic blocks can be arranged in tandem with each memory block of the array of trusted memory blocks. Also, the logic unit of the array of trusted logic blocks can comprise an 8x1 multiplexer. In another embodiment, the ASIC structure includes non-logic structures occupying a space of the ASIC structure that is devoid of active logic circuits. The non-logic structures can comprise filter capacitors.

In accordance with still another aspect of the present invention, a process of testing and verifying a plurality of truth table logic blocks. The process includes a plurality of memory test address signals and a scan select signal are coupled to the selection line of the plurality of switches. The trusted memory block can include a buffer circuit following the scan D flip flop. In addition, the plurality of switches can comprise a triad of 2 to 1 multiplexers that are arranged in tandem.
inputs of a logic structure is provided. The process comprises loading a test pattern into a chain of memory blocks configured into a scan chain. A test address is loaded to a plurality of logic units. A test enable signal is set to a high. The test pattern is unloaded from the chain of memory blocks of the scan chain. The chain of memory blocks can comprise a plurality of switches comprising a plurality of input lines, a selection line and an output line, a scan D flip-flop coupled to the output line of one of the plurality of switches and a plurality of selection node input signals and a scan data signal are coupled to the plurality of input lines and a plurality of memory test address signals and a scan select signal are coupled to the selection line of the plurality of switches. The process can include testing a capacitance of the logic structure and determining a change in capacitance from an expected capacitance.

Other features of the present invention will become apparent from consideration of the following description taken in conjunction with the accompanying drawings.

BRIEF DESCRIPTION OF THE DRAWINGS

The novel features of the invention are set forth in the appended claims. However, for purpose of explanation, several embodiments of the invention are set forth in the following figures.

FIG. 1 illustrates a functional block diagram of a diagnosable structured ASIC array in accordance with an embodiment of the invention.

FIG. 1A illustrates a detail view of a base group of the structured ASIC array.

FIG. 2 illustrates a trusted logic block for the diagnosable structured ASIC array.

FIG. 3 illustrates a memory block or diagnostic circuit for programmable control signals in accordance with the present invention.

FIG. 4 illustrates a base structure of a logic cell in accordance with the present invention.

FIG. 4A illustrates an alternative embodiment of a basic structure of a logic cell in accordance with the present invention.

FIG. 5 illustrates a process flow diagram for a testing process of the base cell in accordance with the present invention.

FIG. 6 illustrates subversive logic capable of infecting logic circuits of prior art base cells.

FIGS. 7A-7C illustrate an example layout of a base group comprising a modular layout of base cells for a very dense standard cell. The base group comprises an array of base cells which is routed throughout each base group. The base group generally comprises an array of base cells duplicated and arranged in an array to form a core of a structured ASIC circuit such as the IC chip core. The base cell can be configured as a very dense standard cell by utilizing a selection algebra that optimizes a layout of the gates (not shown) comprising the base cell, described in further detail in U.S. Pat. Nos. 6,779,158 and 6,792,589 both of which are hereby incorporated by reference. Also see S. Whitaker, L. Miles, J. Gambles, G. Donohoe and L. Davis, High Density Standard Cell Library, NASA Symposium on VLSI Design, Paper TA5, May 2003.

The base cells comprise a logic block or a trusted logic block in tandem with a memory block or a trusted memory block. The logic blocks are configured to perform a logic function as will be described in relation to an embodiment illustrated in FIG. 2. The memory blocks facilitate storage of a logic state, which can be transferred from the logic blocks to the memory blocks. The memory blocks will be described in relation to an embodiment illustrated in FIG. 3. In certain applications of the ASIC structure, a number of the logic blocks and the memory blocks are left unused. The unused logic blocks and memory blocks can be configured in a number of ways that determine testing as explained below they can be observed and controlled. An example of configuration for the unused logic cells and memory block can comprise a shift register.

Turning to FIG. 2, a trusted logic block can be configured to perform a logic function as will be described in relation to an embodiment illustrated in FIG. 2. The trusted logic block comprises a logic core configured to follow the logic unit. The trusted logic block comprises a number of elements as described in further detail in FIGS. 3-7C. The trusted logic block comprises a number of elements as described in further detail in FIGS. 3-7C. The trusted logic block comprises a number of elements as described in further detail in FIGS. 3-7C.
programmable truth table inputs 17-10. The truth table inputs 17-10 can be programmed to implement any number of boolean functions, e.g., AND, OR, XOR, as known by a person of ordinary skill in the art. The inputs 17-10 are programmed with a logic 1 or 0 by connecting the inputs 17-10 to Vss or Vdd. Alternatively, the inputs 17-10 can be driven by a variety of signals. For example, outputs of other flip flops or input signals to the IC chip core 100. The selector pins Y2, Y1, Y0 decode to select a particular truth table input 17-10, which is then produced at the output pin 214.

The plurality of switching units 230, 240, 250 comprise two input lines each 230A/230B, 240A/240B, 250A/250B, respectively, selector lines 230C, 240C, 250C respectively and outputs 230D, 240D, 250D, respectively. The plurality of switching units 230, 240, 250 comprise logic units capable of passing either a high or low logic signal felt on either of the two input lines 230A/230B, 240A/240B, 250A/250B. In an exemplary embodiment, the switching units 230, 240, 250 each comprise a 2 to 1 multiplexer. The test bus 260 comprises a test enable signal TE, and test address signals TA2—TA0. The test enable signal TE is used to put the base cell 200 into a test mode. The test enable signal TE is coupled to the selection lines 230C, 240C, 250C. The test address signals TA2—TA0 decode to select a particular truth table input 17-10. The program control bus 280 comprises program control signals PC2—PC0, which decode to select a particular truth table input 17-10 when the base cell 200 is in a non-test mode. The outputs 230D, 240D, 250D are coupled to the selector pins Y2, Y1, Y0 of the logic unit 210 such that a selector node input signal is felt at each of the selector pins Y2, Y1, Y0.

Turning to FIG. 3, a trusted memory block or a diagnostic circuit 300 is shown for the selector pins Y2, Y1, Y0 in accordance with the present invention. The diagnostic circuit 300 facilitates diagnosis and/or observation on a connectivity of the selector pins Y2, Y1, Y0. In this regard, the diagnostic circuit 300 maximizes the ability to determine logic values loaded into the selector pins Y2, Y1, Y0. The diagnostic circuit 300 can be configured in tandem with the trusted logic block 200 to receive the output pin 214 signal of the logic unit 210. The diagnostic circuit 300 generally comprises an array of logic circuits 310, 320, 330 coupled at the scan data pin SD of a scan D flip flop 340. Also included, is a memory test bus 360 comprising memory test address signals MTA2, MTA1, MTA0 and a scan select signal SS. The scan D flip flop 340 includes a ‘D’ input, a scan enable pin SE, a clock input CK, an output ‘Q’ and the scan data pin SD. A 1x buffer 350 is coupled to the output ‘Q’ of the scan D flip flop 340. In an exemplary embodiment, the logic circuits 310, 320, 330 comprise 2 to 1 multiplexers. The selector pins Y2, Y1, Y0 and a scan data signal SD are used as inputs to the logic circuits 310, 320, 330 as shown. The test address signals TA2, TA1 and a scan select signal SS are used in switching the logic circuits 310, 320, 330. The scan select signal SS is used to put the diagnostic circuit 300 in a test mode. A ‘scanned data in’ signal SDI is used to scan out data that is entered on the selector pins Y2, Y1, Y0. The scanned out data is scanned into the scan data SD pin of the scan D flip flop 340.

Turning now to FIG. 4, a basic structure of a logic cell 400 in accordance with the present invention is shown. The logic cell 400 comprises a combinational logic block 410 in communication with a storage element 420. The combinational logic block 410 comprises a design logic module 412 and a testable logic module 414. The design logic module 412 comprises active logic circuits (not shown) that implement a basic logic function, e.g., AND, OR, XOR. The testable logic module 414 comprises active logic circuits 414a that implement a testable function, for example, a shift register function. Alternatively, as shown in FIG. 4A, the logic cell 400 comprises a combinational logic block 410 and the storage element 420. The combinational logic block 410 includes non-logic structures 416. The non-logic structures 416 can occupy the space of the logic block 410 that remains after the design logic module 412 and the testable logic module 414 have been formed. The non-logic structures 416 prevent the insertion of shadow active electronics (not shown) in the logic block 410. In one embodiment, the non-logic structures 416 can comprise metal filler (not shown) that will render the insertion of shadow active electronics ineffective since no metal interconnects could be used to bring a shadow signal to the shadow electronics. Further, an attempt by an external agent to “cut out” a section of metal, which is below metal that is visually observable, would be ineffective for the same reason of being surrounded by metal. Alternatively, the non-logic structures 416 can comprise filter capacitors 416a. The filter capacitors 416a are configured using methods known to a person of skill in the art.

Turning to FIG. 5, a process flow diagram is illustrated for a testing process 500 for the base cell 140 (see FIG. 1A). A “scan chain” is a method to facilitate testing of the base cell 140 subsequent to fabrication. The method involves coupling the memory block 300 with memory blocks (not shown) of every other base cell 140 of the structured IC chip core 100. The coupled memory blocks (not shown) form a testable function, e.g., a shift register. This testable function enables testing of the connectivity of the truth table inputs 17-10. The coupled memory units facilitate loading or shifting a test pattern into the coupled memory units or the “scan chain.” The coupled memory units (not shown) can then be observed to read out data contained within each memory unit. The input pin 116 (see FIG. 1) of the IC chip core 100 comprises program control signals

- 10, 10
- 25, 25
- 30, 30
- 35, 35
- 40, 40
- 45, 45
- 50, 50
- 55, 55
- 60, 60
- 65, 65
photomasks used to produce physical ICs in a semiconductor fabrication process. The shadow Mux 620 comprises logic gates which alter the original design as envisioned by an original designer. The shadow Mux 620 comprises logic gates which alter the original design as envisioned by an original designer. The control Mux 630 acts as a switch asserting either an output of the original Mux 610 or an output of the shadow Mux 620. The external Mux control 640 is a select signal used to pass the output of the shadow Mux 620 instead of the output of the original Mux 610. The external Mux control 640 can be a control signal that is hidden, e.g., within a power pad.

The shadow Mux 620, control Mux 630 and the external Mux control 640 are clandestine circuits that can have been inserted to subvert the original design. These clandestine circuits can be inserted at the foundry level during IC chip fabrication. Testing as described herein would detect these clandestine circuits.

It is preferred that only metal layer processing except for formation of vias occur such that no additional active devices are added to the final ASIC device.

Turning to FIGS. 7A-7C, an example layout of a base group 700 is shown. The base group 700 includes logic blocks LB and memory blocks MB arranged in tandem in 6x4 array. Included in the layout of the base group 700 is Vss lines, Vdd lines and 3x buffers configured between the Vss and Vdd line. The base group 700 can also include filter capacitors 705 configured between the Vss and Vdd lines.

While the invention has been described with reference to numerous specific details, one of ordinary skill in the art will recognize that the invention can be embodied in other specific forms without departing from the spirit of the invention. Thus, one of ordinary skill in the art will understand that the invention is not to be limited by the foregoing illustrative details, but rather is to be defined by the appended claims.

What is claimed is:

1. A base cell structure comprising:
   a logic unit comprising a plurality of input nodes, a plurality of selection nodes, and an output node; a plurality of switches coupled to the selection nodes, the switches comprising a plurality of input lines, a selection line and an output line; a memory cell coupled to the output node; and a test address bus and a program control bus coupled to the plurality of input lines and the selection line of the plurality of switches; wherein a state on each of the plurality of input nodes is verifiably loaded and read from the memory cell, wherein the plurality of switches comprise a triad of multiplexers that are coupled to the selection nodes via the output line of each of the switches.

2. The base cell structure of claim 1, further comprising a test enable signal coupled to the selection line of the plurality of switches.

3. The base cell structure of claim 1, wherein the logic unit comprises an 8x1 multiplexer.

4. The base cell structure of claim 1, wherein the plurality of switches comprise 2x1 multiplexers.

5. A trusted memory block comprising:
   a plurality of switches comprising a plurality of input lines, a selection line and an output line;
a scan D flip flop coupled to the output line of one of the plurality of switches; and a plurality of selection node input signals and a scan data signal coupled to the plurality of input lines and a plurality of memory test address signals and a scan select signal coupled to the selection line of the plurality of switches, wherein the plurality of switches comprise a triad of multiplexers that are arranged in tandem.

6. The trusted memory block of claim 5, further comprising a buffer circuit following the scan D flip flop.

7. The trusted memory block of claim 5, wherein the triad of multiplexers comprise 2 to 1 multiplexers.

8. A logic structure comprising:

- an array of trusted logic blocks comprising a logic unit
- comprising a plurality of input nodes, a plurality of selection nodes, and an output node, a plurality of switches coupled to the selection nodes, the switches comprising a plurality of input lines, a selection line and an output line, and a test address bus and a program control bus coupled to the plurality of input lines and the selection line of the plurality of switches; and

an array of trusted memory blocks comprising a plurality of switches comprising a plurality of input lines, a selection line and an output line, a scan D flip flop coupled to the output line of one of the plurality of switches, and a plurality of memory test address signals and a scan data signal coupled to the plurality of input lines and a plurality of selection node input signals, respectively; and

9. The logic structure of claim 8, wherein each logic block of the array of trusted logic blocks is arranged in tandem with each memory block of the array of trusted memory blocks.

10. The logic structure of claim 8, wherein the logic unit of the array of trusted logic blocks comprises an 8x1 multiplexer.

11. The logic structure of claim 8, further comprising 9x buffers and 3x buffers on a periphery of the logic structure.

12. The logic structure of claim 8, further comprising a buffer circuit following each of the logic units and scan D flip flops.

13. The logic structure of claim 8, further comprising non-logic structures occupying a space of logic structure that is devoid of active logic circuits.

14. The logic structure of claim 13, wherein the non-logic structures comprise filter capacitors.

15. The logic structure of claim 13, further comprising a plurality of unused trusted logic blocks and unused trusted memory blocks configured into a testable function.

16. The logic structure of claim 15, wherein the testable function comprises a shift register.

17. An application specific integrated circuit (ASIC) structure comprising:

- an array of base groups each including a logic structure comprising:
- an array of trusted logic blocks comprising a logic unit comprising a plurality of input nodes, a plurality of selection nodes, and an output node, a plurality of switches coupled to the selection nodes, the switches comprising a plurality of input lines, a selection line and an output line, and a test address bus and a program control bus coupled to the plurality of input lines and the selection line of the plurality of switches; and an array of trusted memory blocks comprising a plurality of switches comprising a plurality of input lines, a selection line and an output line, a scan D flip flop coupled to the output line of one of the plurality of switches, and a plurality of memory test address signals and a scan data signal coupled to the plurality of input lines and a plurality of selection node input signals, respectively; and

wherein the array of trusted logic blocks are coupled with the array of trusted memory blocks via the plurality of selection nodes and the plurality of selection node input signals, respectively.

18. The ASIC structure of claim 17, wherein each logic block of the array of trusted logic blocks is arranged in tandem with each memory block of the array of trusted memory blocks.

19. The ASIC structure of claim 17, wherein the logic unit of the array of trusted logic blocks comprises an 8x1 multiplexer.

20. The ASIC structure of claim 17, further comprising non-logic structures occupying a space of ASIC structure that is devoid of active logic circuits.

21. The ASIC structure of claim 20, wherein the non-logic structures comprise filter capacitors.

22. The ASIC structure of claim 17, further comprising a plurality of unused trusted logic blocks and unused trusted memory blocks configured into a testable function.

23. The ASIC structure of claim 22, wherein the testable function comprises a shift register.

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